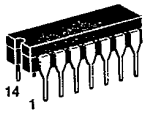
MHQ4002A

CASE 632-02, STYLE 1
TO-116



QUAD
MEMORY DRIVER TRANSISTOR

NPN SILICON

Refer to MD3725 for graphs.

5

MAXIMUM RATINGS

Rating	Symbol	Value		Unit
Collector-Emitter Voltage	V_{CEO}	45		Vdc
Collector-Emitter Voltage	V_{CES}	70		Vdc
Collector-Base Voltage	V_{CBO}	70		Vdc
Emitter-Base Voltage	V_{EBO}	6.0		Vdc
Collector Current — Continuous	I_C	1.5		Adc
		Each Transistor	Four Transistors Equal Power	
Total Device Dissipation @ T_A = 25°C Derate above 25°C	P_D	750 4.3	2500 14.3	mW mW/°C
Total Device Dissipation @ T_C = 25°C Derate above 25°C	P_D	1.2 6.86	4.0 22.8	Watts mW/°C
Operating and Storage Junction Temperature Range	T_J, T_{stg}	−55 to +200		°C

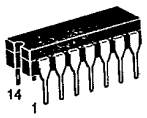
ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise noted.)

Characteristic		Symbol	Min	Typ	Max	Unit
OFF CHARACTERISTICS						
Collector-Emitter Breakdown Voltage(1) (I_C = 10 mAdc, I_B = 0)		$V_{(BR)CEO}$	45	—	—	Vdc
Collector-Emitter Breakdown Voltage (I_C = 10 μAdc, V_{BE} = 0)		$V_{(BR)CES}$	70	—	—	Vdc
Collector-Base Breakdown Voltage (I_C = 10 μAdc, I_E = 0)		$V_{(BR)CBO}$	70	—	—	Vdc
Emitter-Base Breakdown Voltage (I_E = 10 μAdc, I_C = 0)		$V_{(BR)EBO}$	6.0	—	—	Vdc
Collector Cutoff Current (V_{CB} = 30 Vdc, I_E = 0)		I_{CBO}	—	—	500	nAdc
ON CHARACTERISTICS(1)						
DC Current Gain	(I_C = 100 mAdc, V_{CE} = 1.0 Vdc) (I_C = 500 mAdc, V_{CE} = 1.0 Vdc) (I_C = 1.0 Adc, V_{CE} = 5.0 Vdc)	h_{FE}	50 30 20	100 60 45	250 — —	—
Collector-Emitter Saturation Voltage	(I_C = 100 mAdc, I_B = 10 mAdc) (I_C = 500 mAdc, I_B = 50 mAdc) (I_C = 1.0 Adc, I_B = 100 mAdc)	$V_{CE(sat)}$	— — —	0.14 0.23 0.36	0.26 0.52 0.95	Vdc
Base-Emitter Saturation Voltage	(I_C = 100 mAdc, I_B = 10 mAdc) (I_C = 500 mAdc, I_B = 50 mAdc) (I_C = 1.0 Adc, I_B = 100 mAdc)	$V_{BE(sat)}$	— 0.8 —	0.75 0.88 1.0	0.86 1.1 1.7	Vdc
SMALL-SIGNAL CHARACTERISTICS						
Current-Gain — Bandwidth Product(1) (I_C = 50 mAdc, V_{CE} = 10 Vdc, f = 100 MHz)		f_T	200	275	—	MHz
Output Capacitance (V_{CB} = 10 Vdc, I_E = 0, f = 1.0 MHz)		C_{obo}	—	5.0	10	pF
Input Capacitance (V_{BE} = 0.5 Vdc, I_C = 0, f = 1.0 MHz)		C_{ibo}	—	55	70	pF
SWITCHING CHARACTERISTICS						
Turn-On Time (V_{CC} = 30 Vdc, I_C = 0.5 Adc, V_{BE} = 3.8 Vdc, I_{B1} = 50 mAdc)		t_{on}	—	30	40	ns
Turn-Off Time (V_{CC} = 30 Vdc, I_C = 0.5 Adc, I_{B1} = I_{B2} = 50 mAdc)		t_{off}	—	60	75	ns

(1) Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2.0%.

MHQ4013
MHQ4014

CASE 632-02, STYLE 1
TO-116



QUAD
MEMORY DRIVER TRANSISTOR

NPN SILICON

Refer to MD3725 for graphs.

5

MAXIMUM RATINGS

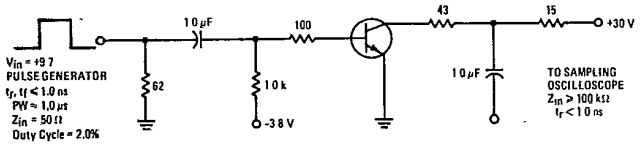
Rating	Symbol	MHQ4013	MHQ4014	Unit
Collector-Emitter Voltage	V_{CEO}	40	45	Vdc
Collector-Emitter Voltage	V_{CES}	60	70	Vdc
Collector-Base Voltage	V_{CBO}	60	70	Vdc
Emitter-Base Voltage	V_{EBO}	6.0		Vdc
Collector Current — Continuous	I_C	1.5		Adc
		Each Transistor	Four Transistors Equal Power	
Total Device Dissipation @ T_A = 25°C Derate above 25°C	P_D	750 4.3	2500 14.3	mW mW/°C
Total Device Dissipation @ T_C = 25°C Derate above 25°C	P_D	1.2 6.86	4.0 22.8	Watts mW/°C
Operating and Storage Junction Temperature Range	T_J, T_{stg}	−55 to +200		°C

ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise noted.)

Characteristic		Symbol	Min	Typ	Max	Unit
OFF CHARACTERISTICS						
Collector-Emitter Breakdown Voltage(1) (I_C = 10 mAdc, I_B = 0)	MHQ4013 MHQ4014	$V_{(BR)CEO}$	40 45	— —	— —	Vdc
Collector-Emitter Breakdown Voltage (I_C = 10 μAdc, V_{BE} = 0)	MHQ4013 MHQ4014	$V_{(BR)CES}$	60 70	— —	— —	Vdc
Collector-Base Breakdown Voltage (I_C = 10 μAdc, I_E = 0)	MHQ4013 MHQ4014	$V_{(BR)CBO}$	60 70	— —	— —	Vdc
Emitter-Base Breakdown Voltage (I_E = 10 μAdc, I_C = 0)		$V_{(BR)EBO}$	6.0	—	—	Vdc
Collector Cutoff Current (V_{CB} = 50 Vdc, I_E = 0)		I_{CBO}	—	—	500	nAdc
ON CHARACTERISTICS(1)						
DC Current Gain	(I_C = 100 mAdc, V_{CE} = 1.0 Vdc) (I_C = 500 mAdc, V_{CE} = 1.0 Vdc) (I_C = 1.0 Adc, V_{CE} = 5.0 Vdc)	h_{FE}	60 35 25	100 65 50	250 — —	—
Collector-Emitter Saturation Voltage	(I_C = 100 mAdc, I_B = 10 mAdc) (I_C = 500 mAdc, I_B = 50 mAdc) (I_C = 1.0 Adc, I_B = 100 mAdc)	$V_{CE(sat)}$	— — —	0.14 0.23 0.36	0.26 0.52 0.95	Vdc
Base-Emitter Saturation Voltage	(I_C = 100 mAdc, I_B = 10 mAdc) (I_C = 500 mAdc, I_B = 50 mAdc) (I_C = 1.0 Adc, I_B = 100 mAdc)	$V_{BE(sat)}$	— 0.8 —	0.75 0.88 1.0	0.86 1.1 1.7	Vdc
SMALL-SIGNAL CHARACTERISTICS						
Current-Gain — Bandwidth Product(1) (I_C = 50 mAdc, V_{CE} = 10 Vdc, f = 100 MHz)		f_T	200	275	—	MHz
Output Capacitance (V_{CB} = 10 Vdc, I_E = 0, f = 1 MHz)		C_{obo}	—	5.0	10	pF
Input Capacitance (V_{BE} = 0.5 Vdc, I_C = 0, f = 1 MHz)		C_{ibo}	—	50	70	pF
SWITCHING CHARACTERISTICS						
Turn-On Time (V_{CC} = 30 Vdc, I_C = 0.5 Adc, $V_{BE(off)}$ = 3.8 Vdc, I_{B1} = 50 mAdc)		t_{on}	—	20	35	ns
Turn-Off Time (V_{CC} = 30 Vdc, I_C = 0.5 Adc, I_{B1} = I_{B2} = 50 mAdc)		t_{off}	—	50	60	ns

(1) Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2.0%.

FIGURE 1 – TURN-ON AND TURN-OFF SWITCHING TIMES TEST CIRCUIT



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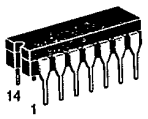
T-43-25

MHQ6001
MHQ6002

CASE 632-02, STYLE 1
TO-116



QUAD COMPLEMENTARY TRANSISTOR

NPN/PNP SILICON

Refer to MHQ2222 for NPN graphs.*

5

MAXIMUM RATINGS

Rating	Symbol	Value		Unit
Collector-Emitter Voltage	V_{CEO}	30		Vdc
Collector-Base Voltage	V_{CBO}	60		Vdc
Emitter-Base Voltage	V_{EBO}	5.0		Vdc
Collector Current — Continuous	I_C	500		mAdc
		Each Transistor	Total Device	
Total Device Dissipation @ T_A = 25°C Derate above 25°C	P_D	0.65 3.72	1.9 10.88	Watts mW/°C
Total Device Dissipation @ T_C = 25°C Derate above 25°C	P_D	1.3 7.43	4.6 26.3	Watts mW/°C
Operating and Storage Junction Temperature Range	T_J, T_{stg}	−65 to +200		°C

ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise noted.)

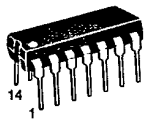
Characteristic		Symbol	Min	Typ	Max	Unit
OFF CHARACTERISTICS						
Collector-Emitter Breakdown Voltage(1) (I_C = 10 mAdc, I_B = 0)		$V_{(BR)CEO}$	30	—	—	Vdc
Collector-Base Breakdown Voltage (I_C = 10 μAdc, I_E = 0)		$V_{(BR)CBO}$	60	—	—	Vdc
Emitter-Base Breakdown Voltage (I_E = 10 μAdc, I_C = 0)		$V_{(BR)EBO}$	5.0	—	—	Vdc
Collector Cutoff Current (V_{CB} = 50 Vdc, I_E = 0)		I_{CBO}	—	—	20	nAdc
Emitter Cutoff Current (V_{BE} = 3.0 Vdc, I_C = 0)		I_{EBO}	—	—	30	nAdc
ON CHARACTERISTICS						
DC Current Gain(1)		h_{FE}				—
(I_C = 1.0 mAdc, V_{CE} = 10 Vdc)	MHQ6001		25	—	—	
	MHQ6002		50	—	—	
(I_C = 10 mAdc, V_{CE} = 10 Vdc)	MHQ6001		35	—	—	
	MHQ6002		75	—	—	
(I_C = 150 mAdc, V_{CE} = 10 Vdc)	MHQ6001		40	—	—	
	MHQ6002		100	—	—	
(I_C = 300 mAdc, V_{CE} = 10 Vdc)	MHQ6001		20	—	—	
	MHQ6002		30	—	—	
Collector-Emitter Saturation Voltage(1)	(I_C = 150 mAdc, I_B = 15 mAdc)	$V_{CE(sat)}$	—	—	0.4	Vdc
	(I_C = 300 mAdc, I_B = 30 mAdc)		—	—	1.4	
Base-Emitter Saturation Voltage(1)	(I_C = 150 mAdc, I_B = 15 mAdc)	$V_{BE(sat)}$	—	—	1.3	Vdc
	(I_C = 300 mAdc, I_B = 30 mAdc)		—	—	2.0	
SMALL-SIGNAL CHARACTERISTICS						
Current-Gain — Bandwidth Product(1) (I_C = 50 mAdc, V_{CE} = 20 Vdc, f = 100 kHz)		f_T	—	400	—	MHz
Output Capacitance (V_{CB} = 10 Vdc, I_E = 0, f = 1 MHz)	NPN	C_{obo}	—	6.0	—	pF
	PNP		—	4.5	—	
Input Capacitance (V_{BE} = 2.0 Vdc, I_C = 0, f = 1 MHz)	NPN	C_{ibo}	—	20	—	pF
	PNP		—	17	—	
SWITCHING CHARACTERISTICS						
Turn-On Time (V_{CC} = 30 Vdc, V_{BE} = 0.5 Vdc, I_C = 150 mAdc, I_{B1} = 15 mAdc)		t_{on}	—	30	—	ns
Turn-Off Time (V_{CC} = 30 Vdc, I_C = 150 mAdc, I_{B1} = I_{B2} = 15 mAdc)		t_{off}	—	225	—	ns
			—	—	—	

(1) Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2.0%.
*Refer to MHQ2907 for PNP graphs.

T-43-25

MPQ918

CASE 646-06, STYLE 1
TO-116



QUAD AMPLIFIER TRANSISTOR

NPN SILICON

Refer to MD918 for graphs.

5

MAXIMUM RATINGS

Rating	Symbol	Value		Unit
Collector-Emitter Voltage	V_{CEO}	15		Vdc
Collector-Base Voltage	V_{CBO}	30		Vdc
Emitter-Base Voltage	V_{EBO}	3.0		Vdc
Collector Current — Continuous	I_C	50		mAdc
		Each Transistor	Four Transistors Equal Power	
Total Device Dissipation @ T_A = 25°C Derate above 25°C	P_D	500 4.0	900 7.2	mW mW/°C
Total Device Dissipation @ T_C = 25°C Derate above 25°C	P_D	6.7 0.825	2.4 19.2	Watts mW/°C
Operating and Storage Junction Temperature Range	T_J, T_{stg}	−55 to +150		°C

THERMAL CHARACTERISTICS

Characteristic		Junction to Case	Junction to Ambient	Unit
Thermal Resistance	Each Die Effective, 4 Die	151 52	250 134	°C/W °C/W
Coupling Factors	Q1-Q4 or Q2-Q3 Q1-Q2 or Q3-Q4	34 2.0	70 26	% %

ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise noted.)

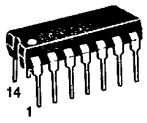
Characteristic	Symbol	Min	Typ	Max	Unit
OFF CHARACTERISTICS					
Collector-Emitter Breakdown Voltage(1) (I_C = 3.0 mAdc, I_B = 0)	$V_{(BR)CEO}$	15	—	—	Vdc
Collector-Base Breakdown Voltage (I_C = 1.0 μAdc, I_E = 0)	$V_{(BR)CBO}$	30	—	—	Vdc
Emitter-Base Breakdown Voltage (I_E = 10 μAdc, I_C = 0)	$V_{(BR)EBO}$	3.0	—	—	Vdc
Collector Cutoff Current (V_{CB} = 15 Vdc, I_E = 0)	I_{CBO}	—	—	10	nAdc
ON CHARACTERISTICS(1)					
DC Current Gain (I_C = 0.1 mAdc, V_{CE} = 1.0 Vdc) (I_C = 3.0 mAdc, V_{CE} = 1.0 Vdc) (I_C = 10 mAdc, V_{CE} = 1.0 Vdc)	h_{FE}	— 20 —	110 80 50	— — —	—
Collector-Emitter Saturation Voltage (I_C = 10 mAdc, I_B = 1.0 mAdc)	$V_{CE(sat)}$	—	0.11	0.4	Vdc
Base-Emitter Saturation Voltage (I_C = 10 mAdc, I_B = 1.0 mAdc)	$V_{BE(sat)}$	—	0.84	1.0	Vdc
SMALL-SIGNAL CHARACTERISTICS					
Current-Gain — Bandwidth Product (I_C = 4.0 mAdc, V_{CE} = 10 Vdc, f = 100 MHz)	f_T	600	850	—	MHz
Output Capacitance (V_{CB} = 10 Vdc, I_E = 0, f = 1 MHz)	C_{obo}	—	0.75	1.7	pF
Input Capacitance (V_{BE} = 0.5 Vdc, I_C = 0, f = 1 MHz)	C_{ibo}	—	1.1	2.0	pF
Noise Figure (I_C = 1.0 mAdc, V_{CE} = 6.0 Vdc, R_G = 400 Ohms, f = 60 MHz)	NF	—	4.0	6.0	dB

(1) Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2.0%.

T-43-25

MPQ1000

CASE 646-06, STYLE 1
TO-116



QUAD AMPLIFIER TRANSISTOR

NPN SILICON

Refer to MD2218 for graphs.

MAXIMUM RATINGS

Rating	Symbol	Value		Unit
Collector-Emitter Voltage	V_{CEO}	20		Vdc
Collector-Base Voltage	V_{CBO}	40		Vdc
Emitter-Base Voltage	V_{EBO}	4.0		Vdc
Collector Current — Continuous	I_C	500		mAdc
		Each Transistor	Four Transistors Equal Power	
Total Device Dissipation @ T_A = 25°C Derate above 25°C	P_D	650 5.18	1250 10	mW mW/°C
Total Device Dissipation @ T_C = 25°C Derate above 25°C	P_D	1.0 8.0	3.0 24	Watts mW/°C
Operating and Storage Junction Temperature Range	T_J, T_{stg}	−55 to +150		°C

THERMAL CHARACTERISTICS

Characteristic		Junction to Case	Junction to Ambient	Unit
Thermal Resistance(1)	Each Die	125	193	°C/W
	Effective, 4 Die	41.6	100	°C/W
Coupling Factors	Q1-Q4 or Q2-Q3	30	60	%
	Q1-Q2 or Q3-Q4	2.0	24	%

(1) $R_{\theta JA}$ is measured with the device soldered into a typical printed circuit board.

ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise noted.)

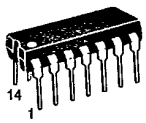
Characteristic	Symbol	Min	Typ	Max	Unit
OFF CHARACTERISTICS					
Collector-Emitter Breakdown Voltage(2) (I_C = 10 mAdc, I_B = 0)	$V_{(BR)CEO}$	20	—	—	Vdc
Collector-Base Breakdown Voltage (I_C = 10 μAdc, I_E = 0)	$V_{(BR)CBO}$	40	—	—	Vdc
Emitter-Base Breakdown Voltage (I_E = 10 μAdc, I_C = 0)	$V_{(BR)EBO}$	4.0	—	—	Vdc
Collector Cutoff Current (V_{CB} = 30 Vdc, I_E = 0)	I_{CBO}	—	—	50	nAdc
Emitter Cutoff Current (V_{EB} = 2.0 Vdc, I_C = 0)	I_{EBO}	—	—	50	nAdc
ON CHARACTERISTICS(2)					
DC Current Gain (I_C = 10 mAdc, V_{CE} = 10 Vdc) (I_C = 50 mAdc, V_{CE} = 10 Vdc) (I_C = 150 mAdc, V_{CE} = 10 Vdc)	h_{FE}	 50 50 40	 — — —	 — — —	—
Collector-Emitter Saturation Voltage (I_C = 150 mAdc, I_B = 15 mAdc)	$V_{CE(sat)}$	—	—	0.5	Vdc
Base-Emitter Saturation Voltage (I_C = 150 mAdc, I_B = 15 mAdc)	$V_{BE(sat)}$	—	—	1.3	Vdc
SMALL-SIGNAL CHARACTERISTICS					
Current-Gain — Bandwidth Product (I_C = 20 mAdc, V_{CE} = 20 Vdc, f = 100 MHz)	f_T	175	—	—	MHz
Output Capacitance (V_{CB} = 10 Vdc, I_E = 0, f = 1 MHz)	C_{obo}	—	—	8.0	pF
Input Capacitance (V_{BE} = 0.5 Vdc, I_C = 0, f = 1 MHz)	C_{ibo}	—	—	30	pF

(2) Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2.0%.

T-43-25

MPQ1500

CASE 646-06, STYLE 1
TO-116



QUAD TRANSISTOR

PNP SILICON

Refer to MPQ2907 for graphs.

5

MAXIMUM RATINGS

Rating	Symbol	Value		Unit
Collector-Emitter Voltage	V_{CEO}	20		Vdc
Collector-Base Voltage	V_{CBO}	40		Vdc
Emitter-Base Voltage	V_{EBO}	4.0		Vdc
Collector Current — Continuous	I_C	500		mAdc
		Each Transistor	Four Transistors Equal Power	
Total Device Dissipation @ T_A = 25°C Derate above 25°C	P_D	0.65 5.18	1.25 8.0	Watts mW/°C
Total Device Dissipation @ T_C = 25°C Derate above 25°C	P_D	1.0 8.0	3.0 24	Watts mW/°C
Operating and Storage Junction Temperature Range	T_J, T_{stg}	−55 to +150		°C

THERMAL CHARACTERISTICS

Characteristic	Junction to Case	Junction to Ambient	Unit
Thermal Resistance(1) Each Die Effective, 4 Die	 125 41.6	 193 100	°C/W
Coupling Factor Q1-Q4 or Q2-Q3 Q1-Q2 or Q3-Q4	 30 2.0	 60 24	%

(1) Junction to ambient data applies for typical printed circuit board mounting.

ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise noted.)

Characteristic	Symbol	Min	Typ	Max	Unit
OFF CHARACTERISTICS					
Collector-Emitter Breakdown Voltage(1) (I_C = 10 mAdc, I_B = 0)	$V_{(BR)CEO}$	20	—	—	Vdc
Collector-Base Breakdown Voltage (I_C = 10 μAdc, I_E = 0)	$V_{(BR)CBO}$	40	—	—	Vdc
Emitter-Base Breakdown Voltage (I_E = 10 μAdc, I_C = 0)	$V_{(BR)EBO}$	4.0	—	—	Vdc
Collector Cutoff Current (V_{CB} = 30 Vdc, I_E = 0)	I_{CBO}	—	—	50	nAdc
Emitter Cutoff Current (V_{EB} = 2.0 Vdc, I_C = 0)	I_{EBO}	—	—	50	nAdc
ON CHARACTERISTICS(1)					
DC Current Gain (I_C = 10 mAdc, V_{CE} = 10 Vdc) (I_C = 50 mAdc, V_{CE} = 10 Vdc) (I_C = 150 mAdc, V_{CE} = 10 Vdc)	h_{FE}	 50 50 40	 100 120 80	 — — —	—
Collector-Emitter Saturation Voltage (I_C = 150 mAdc, I_B = 15 mAdc)	$V_{CE(sat)}$	—	0.22	0.5	Vdc
Base-Emitter Saturation Voltage (I_C = 150 mAdc, I_B = 15 mAdc)	$V_{BE(sat)}$	—	0.89	1.3	Vdc
SMALL-SIGNAL CHARACTERISTICS					
Current-Gain — Bandwidth Product(1) (I_C = 20 mAdc, V_{CE} = 20 Vdc, f = 100 MHz)	f_T	150	300	—	MHz
Output Capacitance (V_{CB} = 10 Vdc, I_E = 0, f = 1 MHz)	C_{obo}	—	4.5	8.0	pF
Input Capacitance (V_{BE} = 0.5 Vdc, I_C = 0, f = 1 MHz)	C_{ibo}	—	17	30	pF

(1) Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2.0%.